

Data integration for point detectors

Ross Angel
Virginia Tech Crystallography Laboratory
Blacksburg VA 24060

rangel@vt.edu

www.crystal.vt.edu

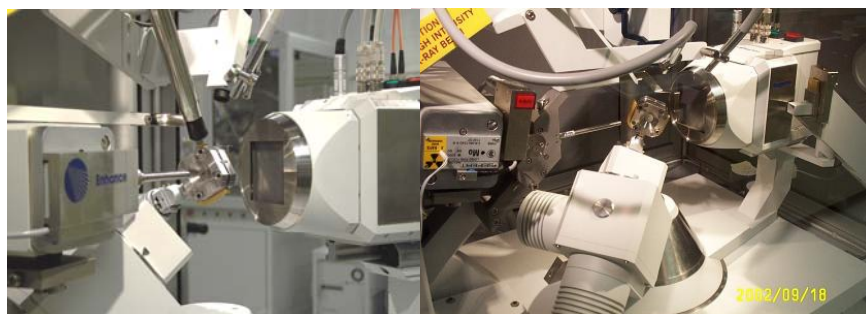
- **General points about PD vs area D**
- **General points about PD integration**
- **Integration with WinIntegrStp**

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Determining structures at high pressure

**Precise intensity data to measure small changes
in structures at high pressures:**



Single-crystal X-ray diffraction.

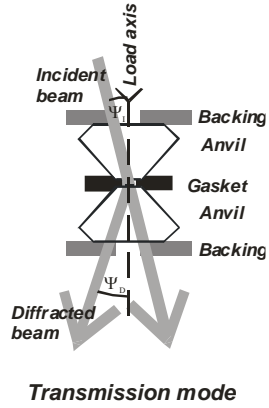
Point and CCD detectors.

Beamlines and in-house

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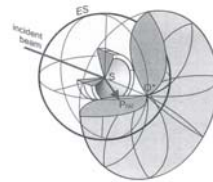
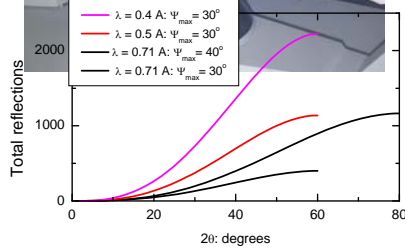
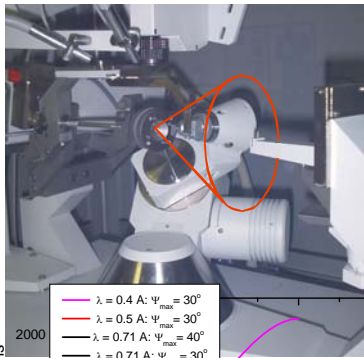
Diamond-anvil geometry



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Limited access



Miletich, RIM volume

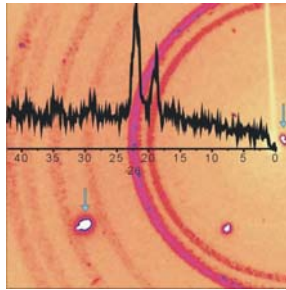
PD is more efficient at collecting data at the edges of accessible space

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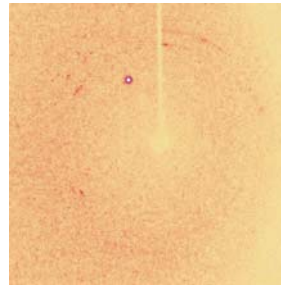
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Reducing background

Everything you see is background!



Conventional DAC with Be seats, steel gasket



DAC with steel seats and rhenium gasket

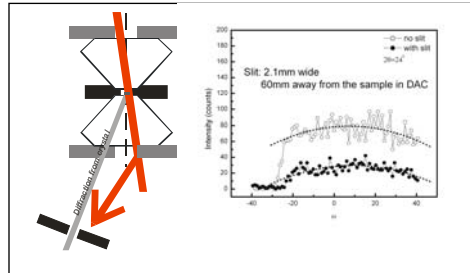
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Reducing background

Use a point detector:

- **Additional collimation**



- **Optimised scan speed**
- **Step scans**
- **Profile fitting**
- **Recovery of weak data**



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Area and Point detectors

Point detector

- Accurate peak positions
 - Centering the DAC
 - Unit-cell parameters
 - Equations of State
- Small unit cells
 - Additional collimation
 - Optimised scan speed
 - Step scans
 - Profile fitting
 - Recovery of weak data

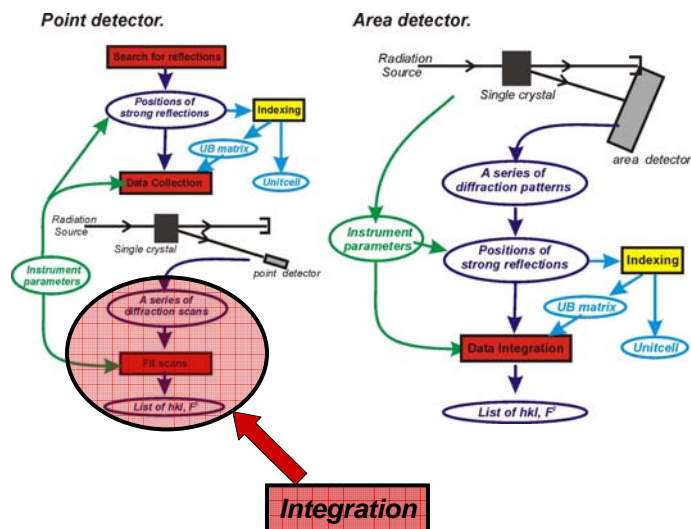
Area

- Poor peak positions
 - Peak hunting
 - Diffuse scattering
- Large unit cells
 - Approx equal intensities
 - Equal scan speeds
 - Faster data collection
- Twins, multiple crystals

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Intensity data collection



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Point detector integration: principles

□ Step scan data file

- many formats
- Header info

□ Data for each reflection

- intensity as $f(\omega)$
- scaling info
- hkl
- setting angles
- auxiliary info
 - (stds, nsteps)
 - scan speed

Integrate

□ Integrated intensity file

- Few formats
- SHELX-HKLF4
- RFINE int

□ Data for each reflection

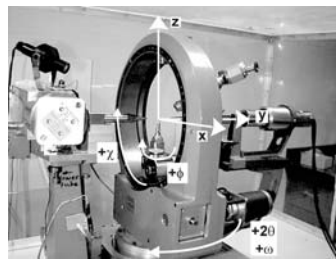
- hkl
- $F^2, \sigma(F^2)$
- beam path info

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Before starting integration

□ Define your instrument



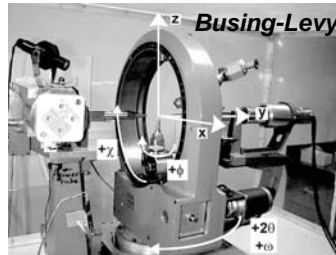
- Wavelength(s) and intensity ratio
- Monochromator
- Attenuator value
- Diffractometer path lengths (RC, RS)
- Normal peak profile parameters

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Defining beam paths for absorption

- The definition of the phi-axis system,
 - Axis directions when diffractometer circles at zero



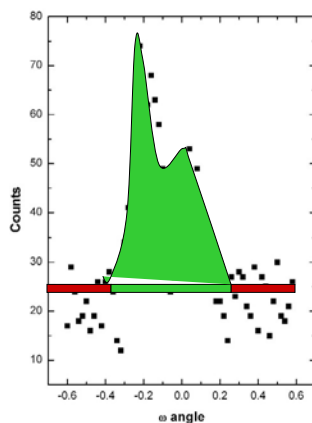
- And you need to know:
 - Type of goniometer (kappa or Eulerian)
 - Circle parities

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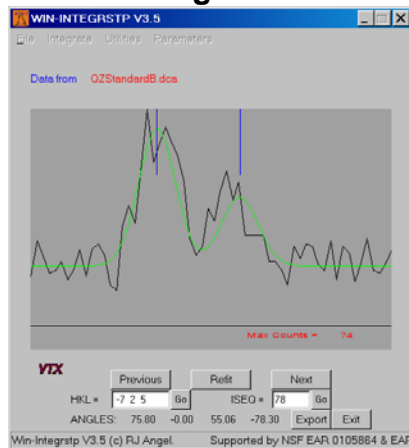
Integration methods

□ B-P-B



Dynamic backgrounds:
Lehman-Larsen

□ Full integration

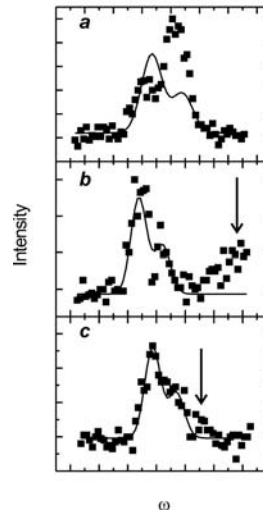


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Advantages of full profile integration

- Learn peak shape from strong reflections
- Test of peak shape: is it real?
 - Do not pass bad reflections
- Recover I even with structured background
- More reliable I for weak reflections



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Integration Programs

- **Commercial**
 - Built in with instrument software
 - Most do BPB, sometimes with LL
 - Fine for good datasets, not so good for DAC
- **Freeware**
 - Several available by email or web (but developers getting old)
 - Please cite freeware properly (not web site source, but a journal article)
- **WinIntegrStp**
 - Developed from IntegrStp and earlier by Larry Finger
 - Windows version since 2001
 - Current version is 3.5
 - Angel RJ (2003) Automated profile analysis for single-crystal diffraction data. Journal of Applied Crystallography, 36:295-300.

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WinIntegrstp features

- Reads most diffractometer data file formats
 - Xcalibur, Stoe, Xscans, Phillips febo, Single, CAD4, old Single
 - (does internal conversion)
 - Can 'easily' add new formats if programmer is supplied with good beer!

- Instrument definition in a text file *.par
 - Can accommodate any instrument configuration

- Full learnt-profile fitting
 - Rejection of bad peaks
 - Recovery of weak reflection data
 - Complex interaction of many controls

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WinIntegrStp

- Download from VTX website
 - www.crystal.vt.edu

- Distribution by zip
 - Manuals and installation instructions
 - Several instrument parameter files
 - Example data file



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